

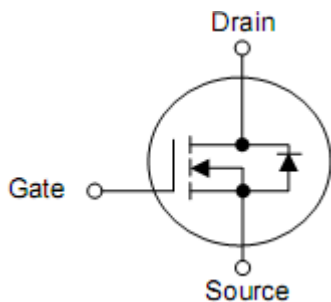
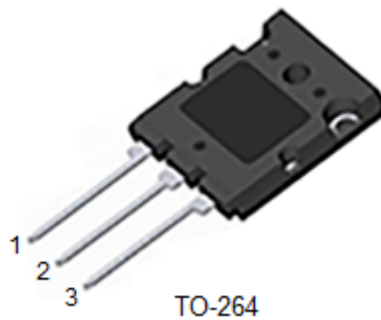
1. Features

- Advanced Planar Process
- $R_{DS(ON)}=480m\Omega(\text{typ.})@V_{GS}=10V$
- Low Gate Charge Minimize Switching Loss
- Rugged Poly silicon Gate Structure

2. Applications

- BLDC Motor Driver
- Electric Welder
- High Efficiency SMPS

3. Symbol



Pin	Function
1	Gate
2	Drain
3	Source

4. Ordering Information

Part Number	Package	Brand
KNK74120A	TO-264	KIA

5. Absolute maximum ratings

$T_C=25^{\circ}\text{C}$ unless otherwise noted

Parameter	Symbol	Rating	Units	
Drain-source voltage	V_{DSS}	1200	V	
Gate-to-Source Voltage	V_{GSS}	± 30	V	
Continuous drain current	$T_C=25^{\circ}\text{C}$	I_D	23	A
	$T_C=100^{\circ}\text{C}$	I_D	14	A
Pulsed Drain Current at $V_{GS}=10\text{V}$ ^{2),4)}	I_{DM}	92	A	
Single pulse avalanche energy	E_{AS}	1600	mJ	
Peak Diode Recovery dv/dt ³⁾	dv/dt	5.0	V/ns	
Power dissipation	P_D	585	W	
Derate above 25°C		4.68	W/ $^{\circ}\text{C}$	
Maximum Temperature for Soldering Leads at 0.063in (1.6mm) from Case for 10 seconds, Package Body for 10 seconds	T_L T_{PAK}	300 260	$^{\circ}\text{C}$	
Operating junction and storage temperature range	T_J, T_{STG}	-55 to 150	$^{\circ}\text{C}$	

Caution: Stresses greater than those listed in the “Absolute Maximum Ratings” may cause permanent damage to the device.

6. Thermal characteristics

Parameter	Symbol	Rating	Unit
Thermal resistance junction-case	$R_{\theta JC}$	0.213	$^{\circ}\text{C}/\text{W}$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	55	$^{\circ}\text{C}/\text{W}$

7. Electrical characteristics

(T_J=25°C unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain-source breakdown voltage	BV _{DSS}	V _{GS} =0V, I _D =250uA	1200	-	-	V
Drain-source leakage current	I _{DSS}	V _{DS} =1200V, V _{GS} =0V	-	-	5	uA
		V _{DS} =960V, T _C =125°C	-	-	125	
Gate-source forward leakage	I _{GSS}	V _{GS} =±30V, V _{DS} =0V	-	-	±100	nA
Drain-source on-resistance ³⁾	R _{DS(on)}	V _{GS} =10V, I _D =12A	-	480	600	mΩ
Gate threshold voltage	V _{GS(TH)}	V _{DS} =V _{GS} , I _D =250uA	2.5	-	4.5	V
Forward Transconductance	g _{FS}	V _{DS} =25V, I _D =12A	-	17.5	-	S
Input capacitance	C _{iss}	V _{DS} =25V, V _{GS} =0V f=1MHz	-	7350	-	pF
Reverse transfer capacitance	C _{rss}		-	55	-	pF
Output capacitance	C _{oss}		-	556	-	pF
Total gate charge	Q _g	V _{DD} =500V, I _D =12A V _{GS} =0~10V	-	185	-	nC
Gate-source charge	Q _{gs}		-	45	-	nC
Gate-drain charge	Q _{gd}		-	56	-	nC
Turn-on delay time	t _{d(on)}	V _{DD} =500V, V _{GS} =10V, R _G =10Ω, I _D =12A	-	60	-	ns
Rise time	t _r		-	112	-	ns
Turn-off delay time	t _{d(off)}		-	64	-	ns
Fall time	t _f		-	100	-	ns
Continuous Source Current ²⁾	I _{SD}	Integral PN-diode in MOSFET	-	-	23	A
Pulsed Source Current ²⁾	I _{SM}		-	-	92	
Diode forward voltage	V _{SD}	I _S =23A, V _{GS} =0V,	-	-	1.5	V
Reverse Recovery Time	t _{rr}	V _{GS} =0V, I _F =23A, dI _F /dt=100A/μs	-	900	-	nS
Reverse Recovery Charge	Q _{rr}		-	2.0	-	uC

Note:

- 1) T_J=+25°C to +150°C.
- 2) Silicon limited current only.
- 3) Package limited current.
- 4) Repetitive rating; pulse width limited by maximum junction temperature.
- 5) Pulse width≤380Us; duty cycle≤2%.

8. Typical operating characteristics

Figure 1. Maximum Transient Thermal Impedance

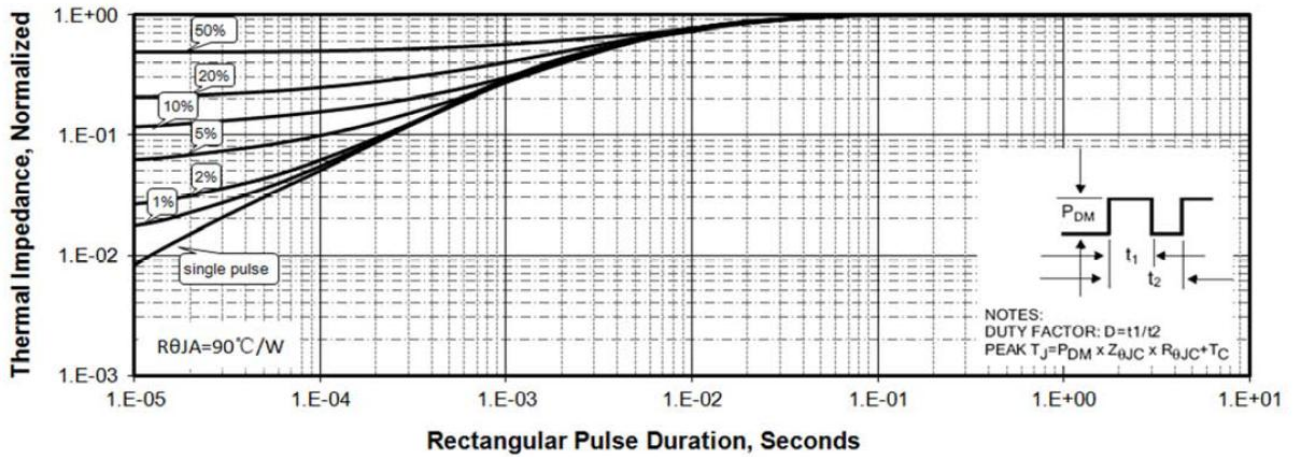


Figure 2. Max. Power Dissipation vs Case Temperature

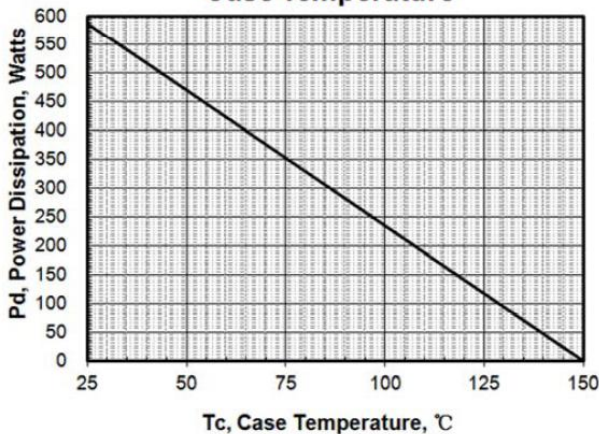


Figure 3. Maximum Continuous Drain Current vs T_c

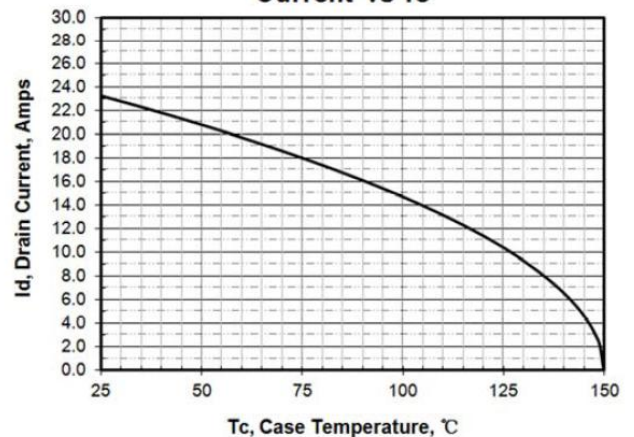


Figure 4. Output Characteristics

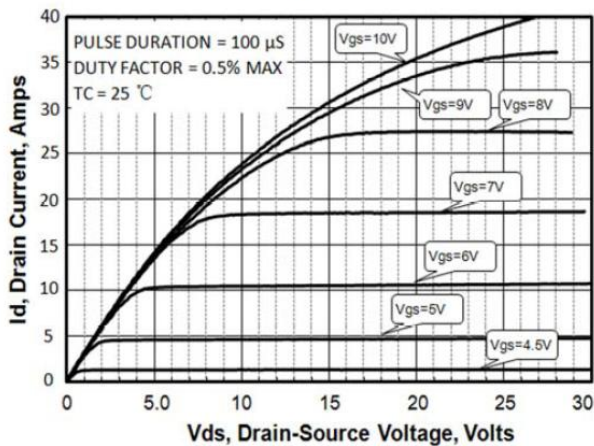


Figure 5. $R_{ds(on)}$ vs Gate Voltage

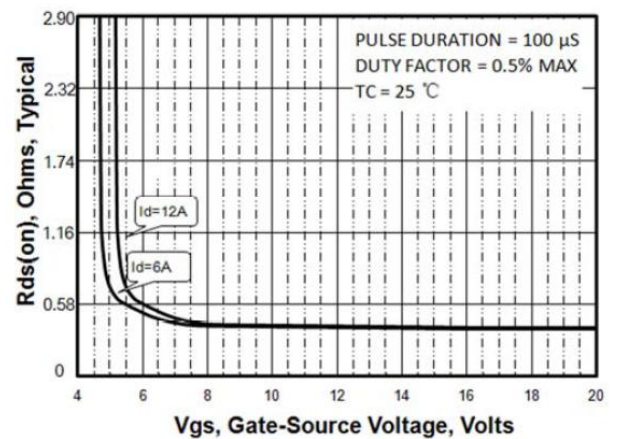


Figure 6. Peak Current Capability

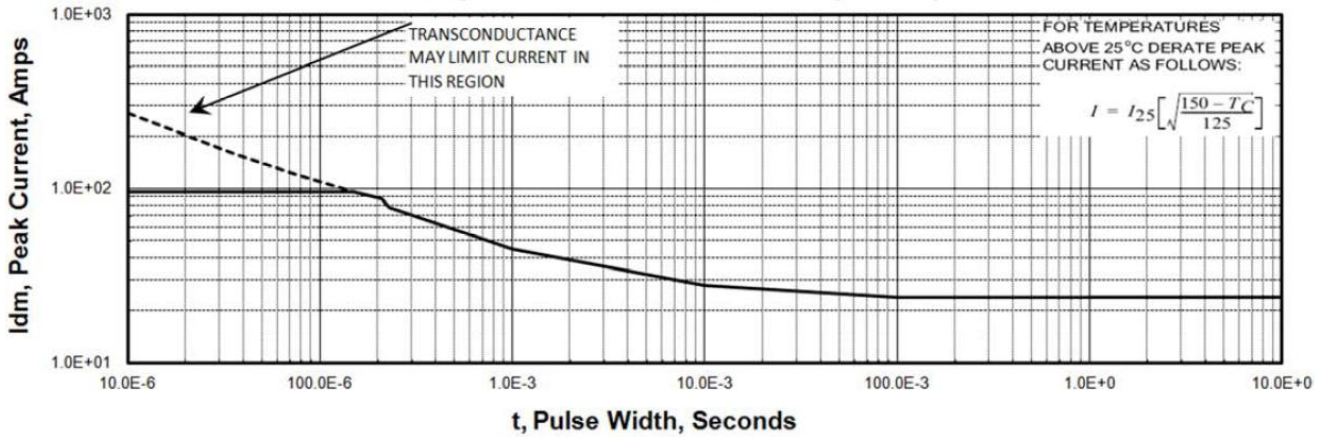


Figure 7. Transfer Characteristics

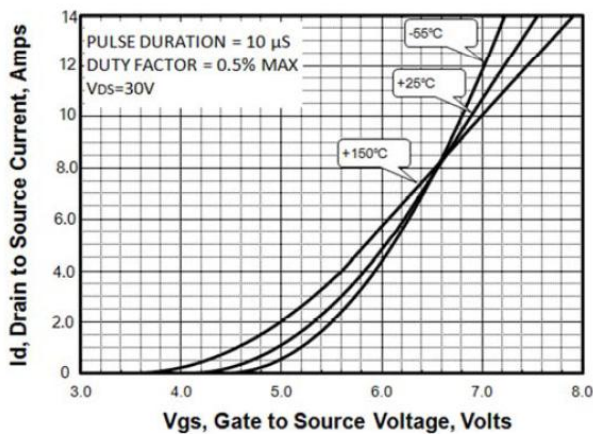


Figure 8. Unclamped Inductive Switching Capability

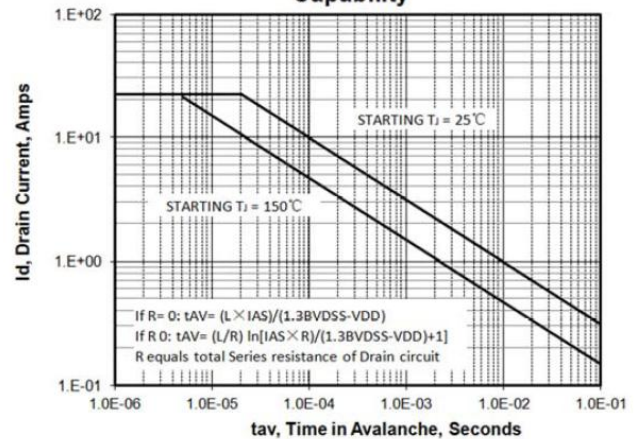


Figure 9. Drain to Source ON Resistance vs Drain Current

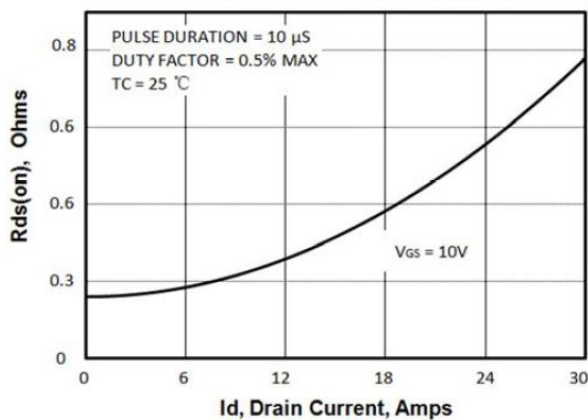


Figure 10. Rds(on) vs Junction Temperature

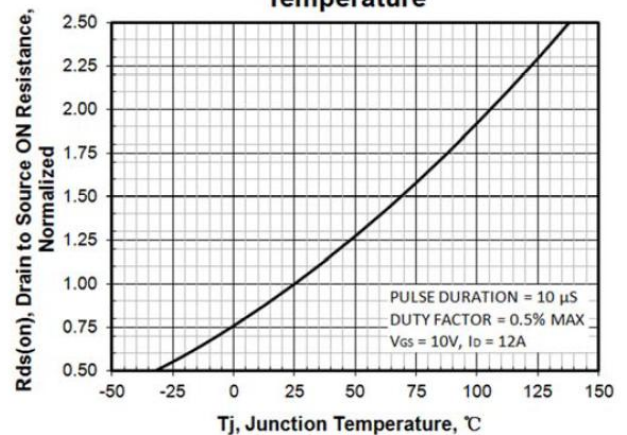


Figure 11. Breakdown Voltage vs Temperature

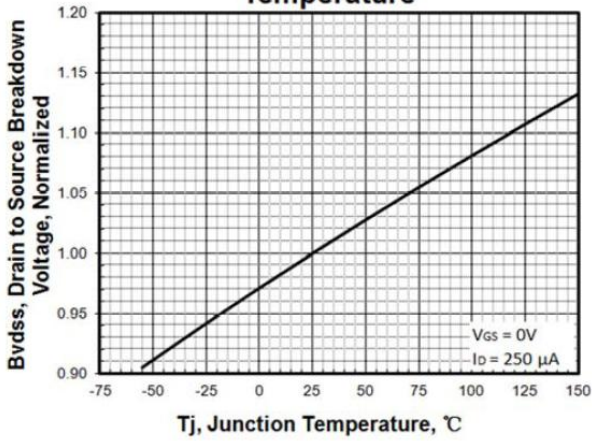


Figure 12. Threshold Voltage vs Temperature

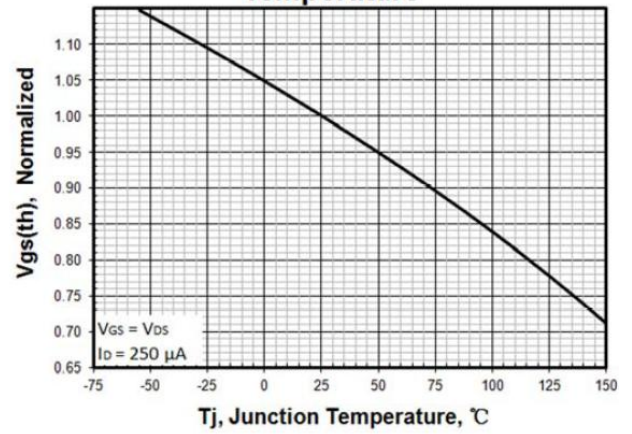


Figure 13 . Maximum Safe Operating Area

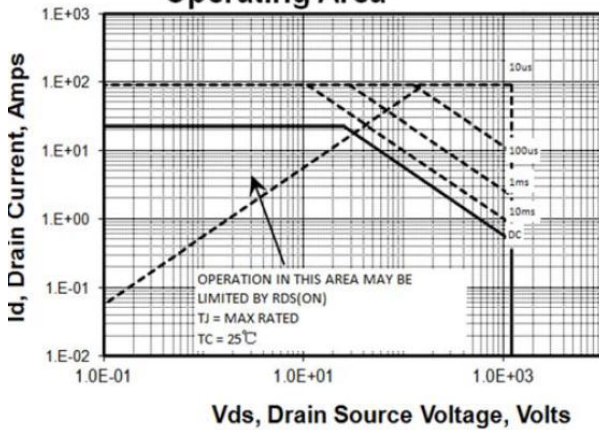


Figure 14. Capacitance vs Vds

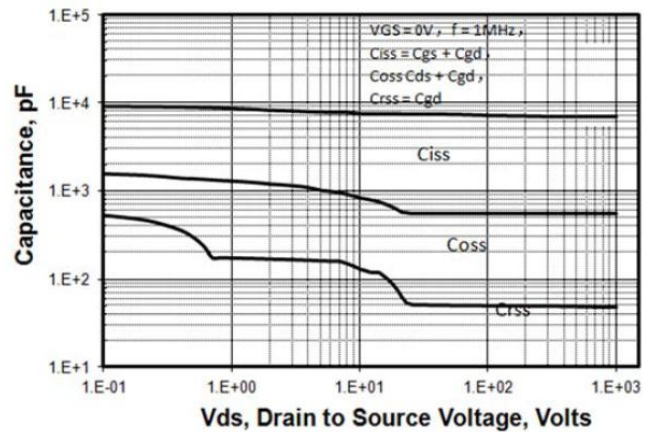


Figure 15 . Typical Gate Charge

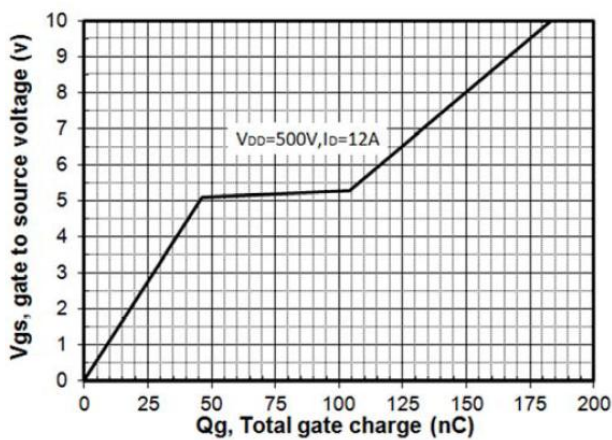
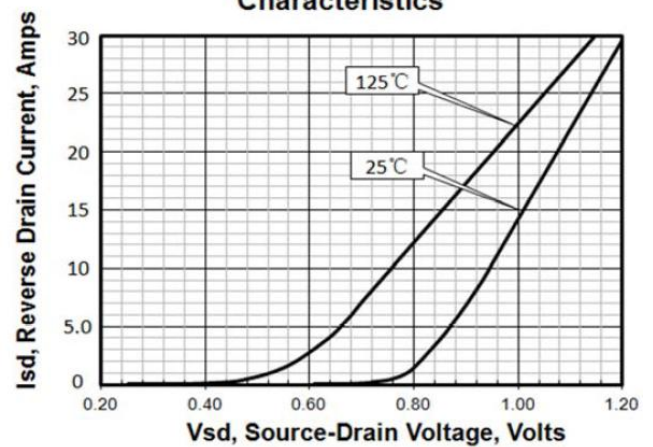


Figure 16. Body Diode Transfer Characteristics



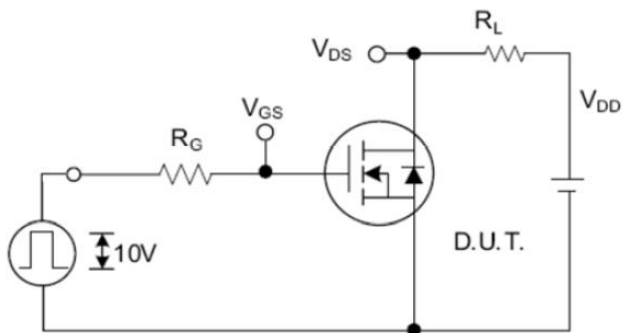


Fig. 2.1 Switching Test Circuit

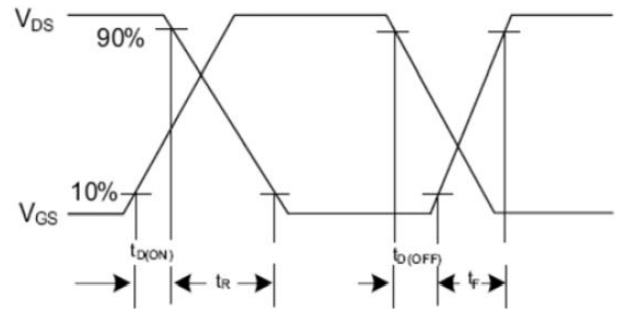


Fig. 2.2 Switching Waveforms

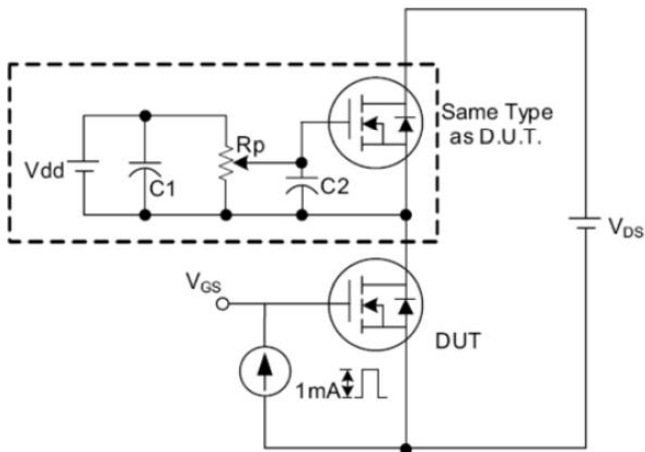


Fig. 3. 1 Gate Charge Test Circuit

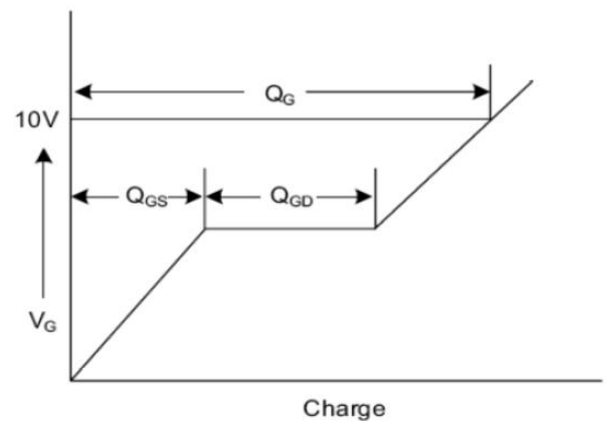


Fig. 3. 2 Gate Charge Waveform

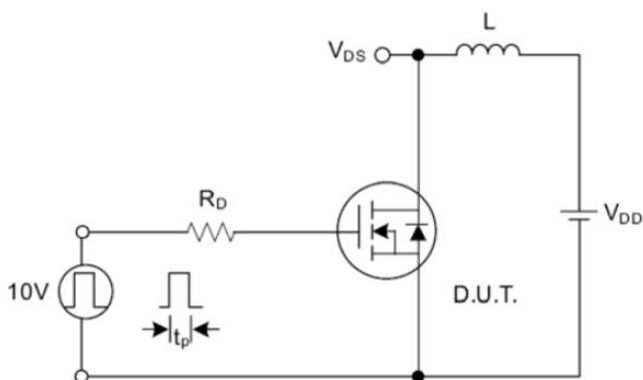


Fig. 4.1 Unclamped Inductive Switching Test Circuit

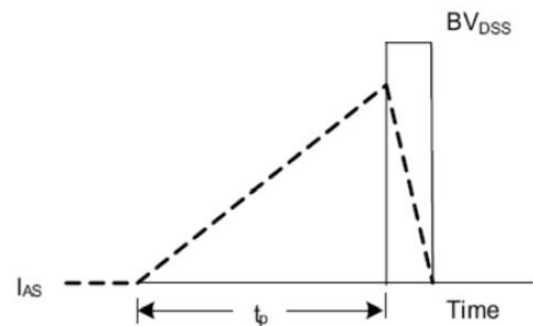


Fig. 4.2 Unclamped Inductive Switching Waveforms